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APPARATUS FOR MEASURING DEFORMING FUNCTION OF CELL

Patent Number: JP1196566
Publication date: 1989-08-08
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Requested Patent: ☐ JP1196566
Application Number: JP19880019545 19880201
Priority Number(s):
IPC Classification: G01N33/49; G01N27/02
EC Classification:
Equivalents: JP2720161B2

Abstract

PURPOSE:To obtain an apparatus capable of well measuring the deforming function of a cell, by providing a means for allowing a cell to pass through a flow passage having a fine caliber and a means for measuring the electrical impedance of a cell-containing medium when the cell passes through said flow passage.
CONSTITUTION:The first electrolytic cell 2 and the second electrolytic cell 5 are provided on a substrate 1 having an electric insulating property so as to communicate with each other through a fine flow passage 6 having a diameter capable of permitting one cell to pass. The first and second electrodes 4, 8 are provided to the first and second electrolytic cells 2, 5 and connected to an AC voltage generating means 10 and an ammeter 11. After the electrolytic cells 2, 5 are filled with an electrolyte containing a cell C, the electrolyte is recirculated by a fluid pump 12. Since the cell C enters the fine flow passage 6 from the first electrolytic cell 2 according to the flow of the electrolyte and the impedance of the system during the passage through the fine flow passage 6 depends on the deforming function of the cell, by detecting the impedance of the system by an impedance operation means 13, the deforming function of the cell can be measured.